Special Issue

Radiation Effects of Advanced Electronic Devices and Circuits

Message from the Guest Editors

Research on the effects of radiation on advanced electronic devices and integrated circuits has increased rapidly over the last few years, resulting in many interesting approaches to the modeling of radiation effects and the design of advanced radiation-hardened electronic devices and integrated circuits. The main aim of this Special Issue is to seek high-quality submissions that highlight emerging applications and address recent breakthroughs in modeling radiation effects in advanced electronic devices and integrated circuits. The topics of interest include, but are not limited to:

- Basic mechanisms, Compact modeling of radiation effects in advanced electronic devices, integrated circuits and novel devices.
- Radiation hardening and fault tolerance for advanced electronic devices, integrated circuits and novel devices.
- Radiation environment influence: space, atmospheric, terrestrial and artificial.
- Radiation effect characterization and radiation hardness assurance testing.
- New developments of interest to the radiation effect community.

Guest Editors Dr. Yaqing Chi

Dr. Li Cai

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Deadline for manuscript submissions

closed (31 December 2023)



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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

Editor-in-Chief

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manuscripts are peer-reviewed and a first decision is provided to authors approximately 16.8 days after submission; acceptance to publication is undertaken in 2.4 days (median values for papers published in this journal in the first half of 2025).